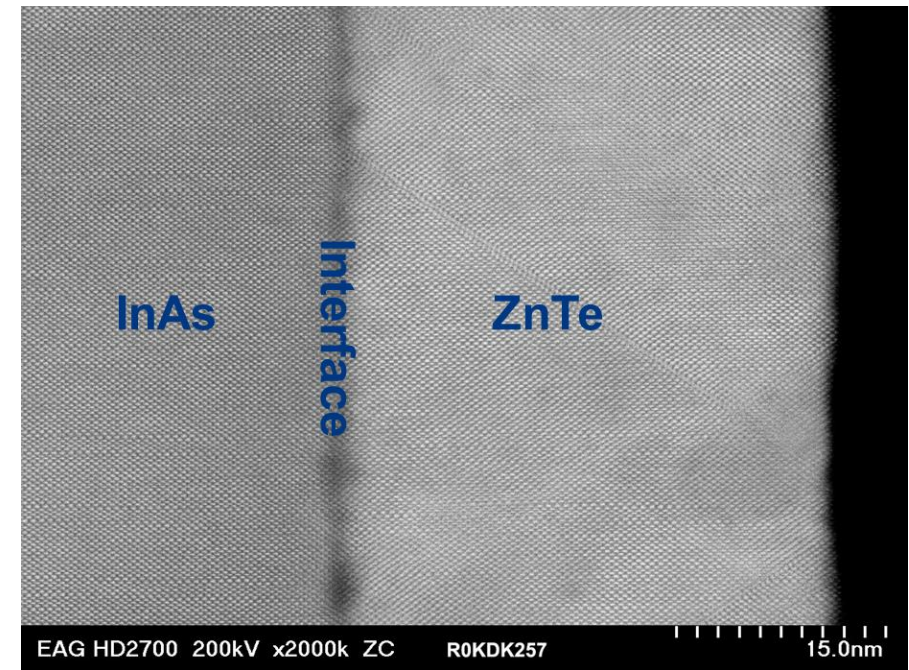
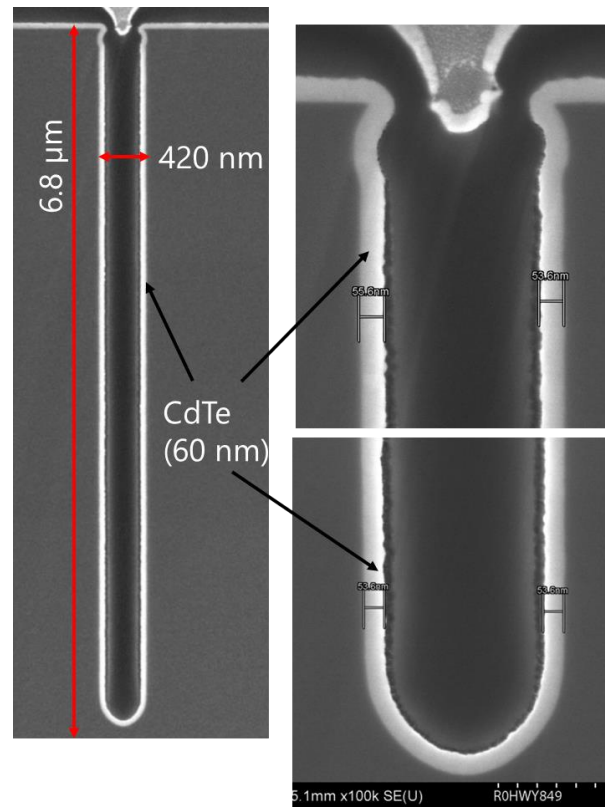
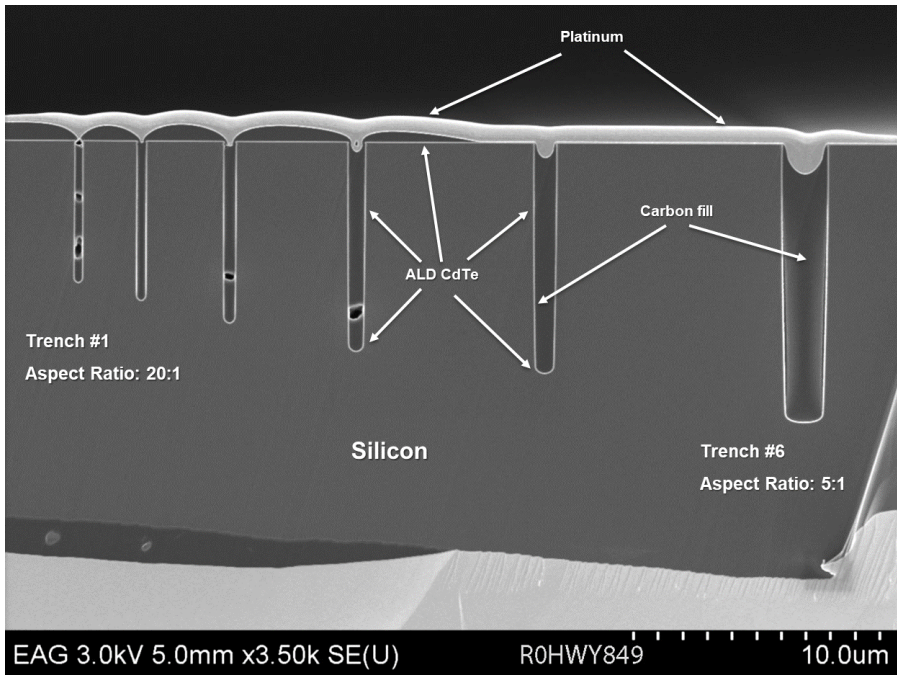


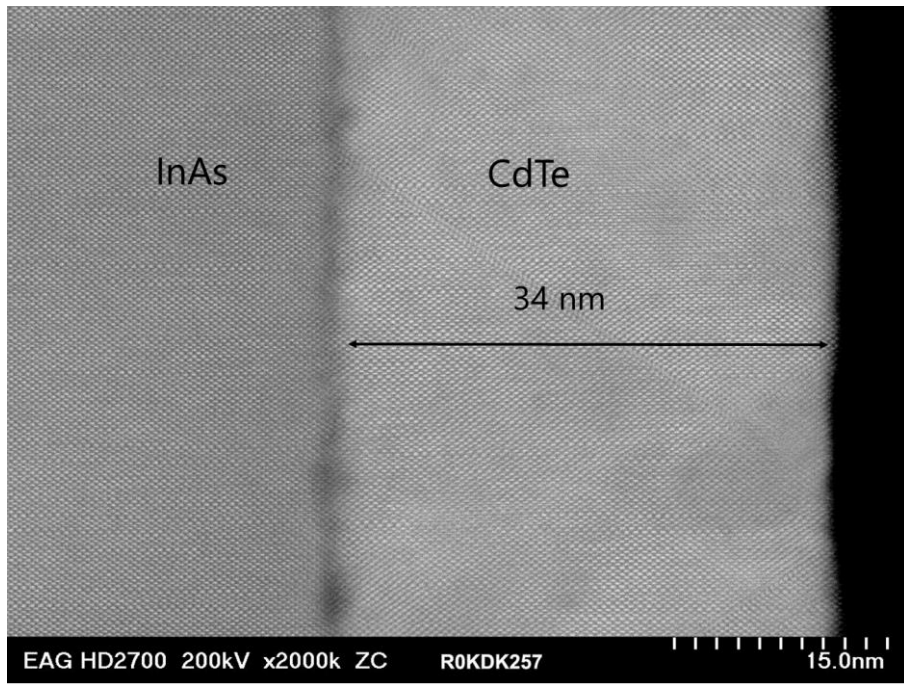
High resolution XRD reciprocal space mapping for ZnTe film grown by ALD at InAs substrate.



Cross-sectional high resolution TEM image of InAs/ZnTe interface for ZnTe film grown by ALD at InAs substrate.



Cross-sectional SEM images of CdTe conformally deposited at trenched Si wafer by ALD.



Cross-sectional high resolution TEM image of InAs/CdTe interface for CdTe film grown by ALD at InAs substrate.